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Extended focused image in white light scanning interference microscopy

Altamar-Mercado, Hernando^a ; Patiño-Vanegas, Alberto^a; Marrugo, Andrés G.^b[Save all to author list](#)^a Facultad de Ciencias Básicas, Universidad Tecnológica de Bolívar, Cartagena, Colombia^b Facultad de Ingeniería, Universidad Tecnológica de Bolívar, Cartagena, Colombia

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We propose a method to obtain a fringe-free extended focused image in white light scanning interference microscopy based on processing the stack of images over a range within the coherence length of the source. © 2019 The Author(s).

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